

# 74LV74

Dual D-type flip-flop with set and reset; positive edge-trigger

Rev. 03 — 28 September 2007

Product data sheet

## 1. General description

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The 74LV74 is a low-voltage Si-gate CMOS device that is pin and function compatible with 74HC74 and 74HCT74.

The device is a dual positive edge triggered D-type flip-flop with individual data (D) inputs, clock (CP) inputs, set ( $\overline{SD}$ ) and ( $\overline{RD}$ ) inputs, and complementary Q and  $\overline{Q}$  outputs.

The set and reset are asynchronous active LOW inputs and operate independently of the clock input. Information on the data input is transferred to the Q output on the LOW-to-HIGH transition of the clock pulse. The D inputs must be stable one set-up time prior to the LOW-to-HIGH clock transition, for predictable operation.

Schmitt trigger action in the clock input makes the circuit highly tolerant of slower clock rise and fall times.

## 2. Features

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- Wide operating voltage: 1.0 V to 5.5 V
- Optimized for low voltage applications: 1.0 V to 3.6 V
- Accepts TTL input levels between  $V_{CC} = 2.7$  V and  $V_{CC} = 3.6$  V
- Typical output ground bounce < 0.8 V at  $V_{CC} = 3.3$  V and  $T_{amb} = 25$  °C
- Typical output  $V_{OH}$  undershoot > 2 V at  $V_{CC} = 3.3$  V and  $T_{amb} = 25$  °C
- ESD protection:
  - ◆ HBM JESD22-A114E exceeds 2000 V
  - ◆ MM JESD22-A115-A exceeds 200 V
- Multiple package options
- Specified from  $-40$  °C to  $+85$  °C and from  $-40$  °C to  $+125$  °C

### 3. Ordering information

Table 1. Ordering information

Type number	Package			
	Temperature range	Name	Description	Version
74LV74N	-40 °C to +125 °C	DIP14	plastic dual in-line package; 14 leads (300 mil)	SOT27-1
74LV74D	-40 °C to +125 °C	SO14	plastic small outline package; 14 leads; body width 3.9 mm	SOT108-1
74LV74DB	-40 °C to +125 °C	SSOP14	plastic shrink small outline package; 14 leads; body width 5.3 mm	SOT337-1
74LV74PW	-40 °C to +125 °C	TSSOP14	plastic thin shrink small outline package; 14 leads; body width 4.4 mm	SOT402-1
74LV74PW	-40 °C to +125 °C	DHVQFN14	plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads; 14 terminals; body 2.5 × 3 × 0.85 mm	SOT762-1

### 4. Functional diagram

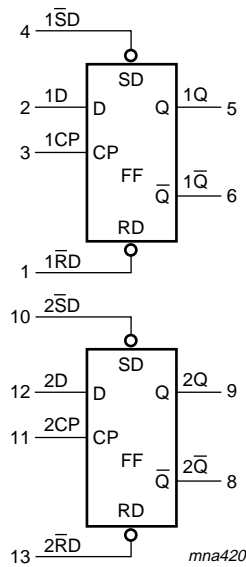


Fig 1. Logic symbol

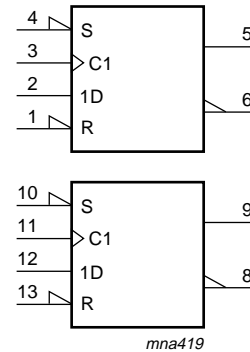
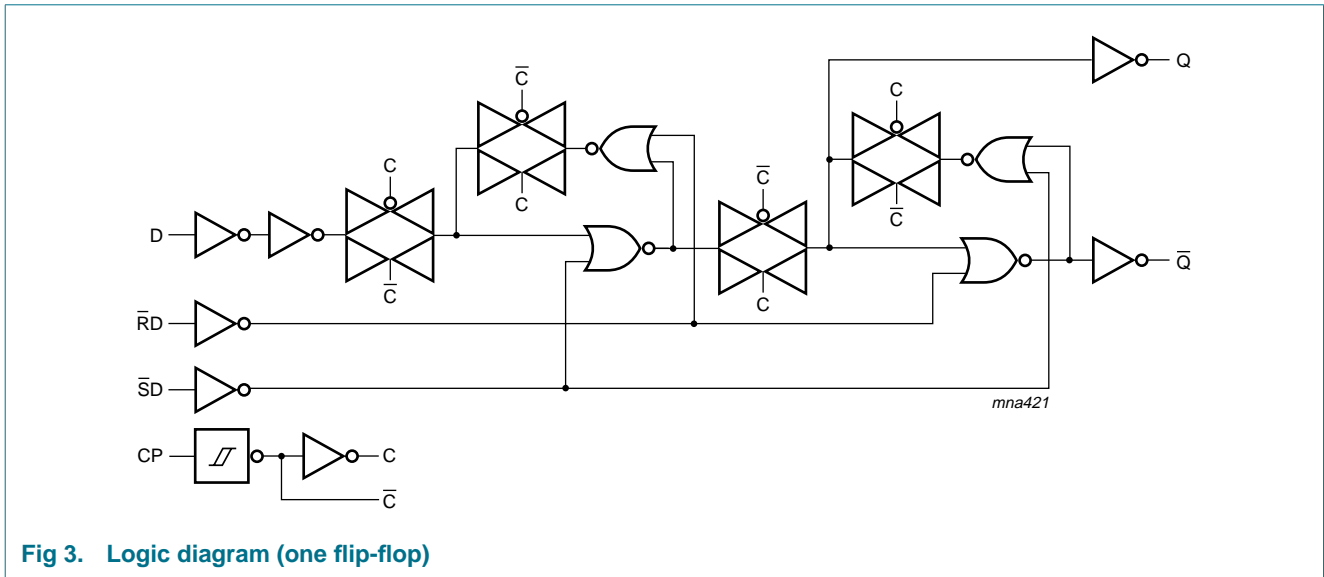
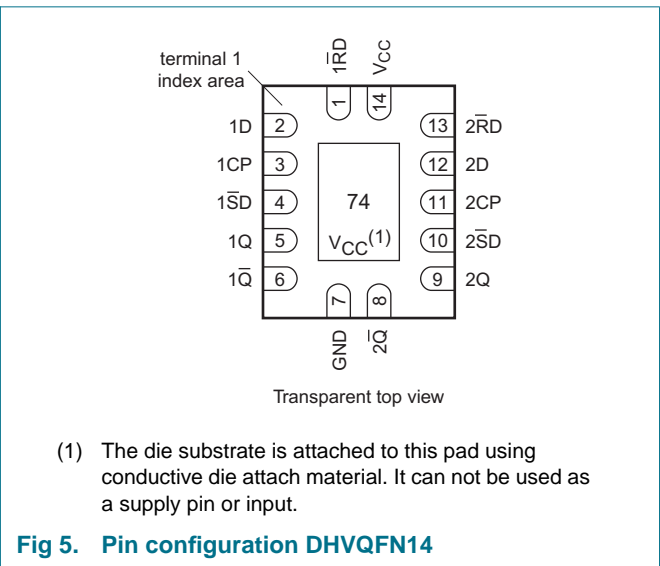
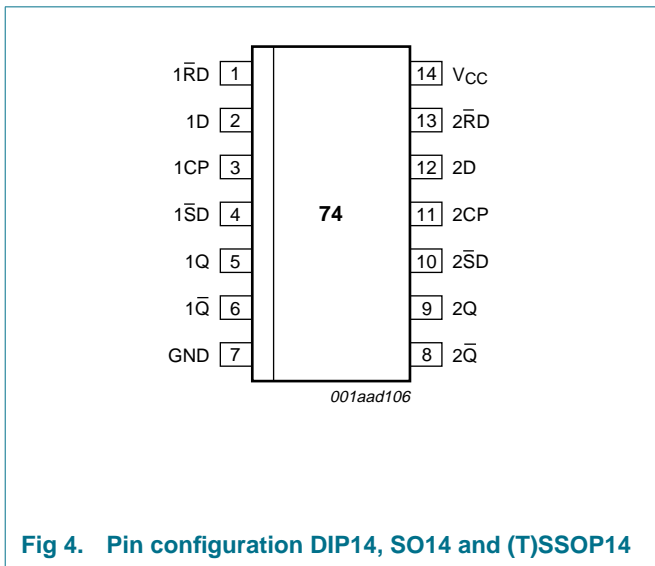


Fig 2. IEC logic symbol



## 5. Pinning information

### 5.1 Pinning



## 5.2 Pin description

Table 2. Pin description

Symbol (n = 1, 2)	Pin	Description
nRD	1, 13	asynchronous reset-direct input (active LOW)
nD	2, 12	data input
nCP	3, 11	clock input (LOW-to-HIGH, edge-triggered)
nSD	4, 10	asynchronous set-direct input (active LOW)
nQ	5, 9	true flip-flop output
nQ̄	6, 8	complement flip-flop output
GND	7	ground (0 V)
V <sub>CC</sub>	14	supply voltage

## 6. Functional description

Table 3. Function table<sup>[1]</sup>

Inputs				Outputs	
nSD	nRD	nCP	nD	nQ	nQ̄
L	H	X	X	H	L
H	L	X	X	L	H
L	L	X	X	H	H

[1] H = HIGH voltage level; L = LOW voltage level; X = don't care

Table 4. Function table<sup>[1]</sup>

Inputs				Outputs	
nSD	nRD	nCP	nD	nQ <sub>n+1</sub>	nQ̄ <sub>n+1</sub>
H	H	↑	L	L	H
H	H	↑	H	H	L

[1] H = HIGH voltage level; L = LOW voltage level  
 ↑ = LOW-to-HIGH transition  
 Q<sub>n+1</sub> = state after the next LOW-to-HIGH CP transition

## 7. Limiting values

**Table 5. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{CC}$	supply voltage		-0.5	+7.0	V
$I_{IK}$	input clamping current	$V_I < -0.5\text{ V}$ or $V_I > V_{CC} + 0.5\text{ V}$	[1] -	$\pm 20$	mA
$I_{OK}$	output clamping current	$V_O < -0.5\text{ V}$ or $V_O > V_{CC} + 0.5\text{ V}$	[1] -	$\pm 50$	mA
$I_O$	output current	$V_O = -0.5\text{ V}$ to $(V_{CC} + 0.5\text{ V})$	-	$\pm 25$	mA
$I_{CC}$	supply current		-	50	mA
$I_{GND}$	ground current		-50	-	mA
$T_{stg}$	storage temperature		-65	+150	°C
$P_{tot}$	total power dissipation	$T_{amb} = -40\text{ °C}$ to $+125\text{ °C}$			
		DIP14 package	[2] -	750	mW
		SO14 package	[3] -	500	mW
		(T)SSOP14 package	[4] -	500	mW
		DHVQFN14 package	[5] -	500	mW

[1] The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

[2]  $P_{tot}$  derates linearly with 12 mW/K above 70 °C.

[3]  $P_{tot}$  derates linearly with 8 mW/K above 70 °C.

[4]  $P_{tot}$  derates linearly with 5.5 mW/K above 60 °C.

[5]  $P_{tot}$  derates linearly with 4.5 mW/K above 60 °C.

## 8. Recommended operating conditions

**Table 6. Recommended operating conditions**

Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{CC}$	supply voltage[1]		1.0	3.3	5.5	V
$V_I$	input voltage		0	-	$V_{CC}$	V
$V_O$	output voltage		0	-	$V_{CC}$	V
$T_{amb}$	ambient temperature		-40	+25	+125	°C
$\Delta t/\Delta V$	input transition rise and fall rate[2]	$V_{CC} = 1.0\text{ V}$ to $2.0\text{ V}$	-	-	500	ns/V
		$V_{CC} = 2.0\text{ V}$ to $2.7\text{ V}$	-	-	200	ns/V
		$V_{CC} = 2.7\text{ V}$ to $3.6\text{ V}$	-	-	100	ns/V
		$V_{CC} = 3.6\text{ V}$ to $5.5\text{ V}$	-	-	50	ns/V

[1] The static characteristics are guaranteed from  $V_{CC} = 1.2\text{ V}$  to  $V_{CC} = 5.5\text{ V}$ , but LV devices are guaranteed to function down to  $V_{CC} = 1.0\text{ V}$  (with input levels GND or  $V_{CC}$ ).

[2] Except for clock inputs, which have Schmitt trigger action..

## 9. Static characteristics

**Table 7. Static characteristics**

Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	-40 °C to +85 °C			-40 °C to +125 °C		Unit
			Min	Typ <sup>[1]</sup>	Max	Min	Max	
V <sub>IH</sub>	HIGH-level input voltage	V <sub>CC</sub> = 1.2 V	0.9	-	-	0.9	-	V
		V <sub>CC</sub> = 2.0 V	1.4	-	-	1.4	-	V
		V <sub>CC</sub> = 2.7 V to 3.6 V	2.0	-	-	2.0	-	V
		V <sub>CC</sub> = 4.5 V to 5.5 V	0.7V <sub>CC</sub>	-	-	0.7V <sub>CC</sub>	-	V
V <sub>IL</sub>	LOW-level input voltage	V <sub>CC</sub> = 1.2 V	-	-	0.3	-	0.3	V
		V <sub>CC</sub> = 2.0 V	-	-	0.6	-	0.6	V
		V <sub>CC</sub> = 2.7 V to 3.6 V	-	-	0.8	-	0.8	V
		V <sub>CC</sub> = 4.5 V to 5.5 V	-	-	0.3V <sub>CC</sub>	-	0.3V <sub>CC</sub>	V
V <sub>OH</sub>	HIGH-level output voltage	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub>						
		I <sub>O</sub> = -100 μA; V <sub>CC</sub> = 1.2 V	-	1.2	-	-	-	V
		I <sub>O</sub> = -100 μA; V <sub>CC</sub> = 2.0 V	1.8	2.0	-	1.8	-	V
		I <sub>O</sub> = -100 μA; V <sub>CC</sub> = 2.7 V	2.5	2.7	-	2.5	-	V
		I <sub>O</sub> = -100 μA; V <sub>CC</sub> = 3.0 V	2.8	3.0	-	2.8	-	V
		I <sub>O</sub> = -100 μA; V <sub>CC</sub> = 4.5 V	4.3	4.5	-	4.3	-	V
		I <sub>O</sub> = -6 mA; V <sub>CC</sub> = 3.0 V	2.4	2.82	-	2.2	-	V
		I <sub>O</sub> = -12 mA; V <sub>CC</sub> = 4.5 V	3.6	4.2	-	3.5	-	V
V <sub>OL</sub>	LOW-level output voltage	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub>						
		I <sub>O</sub> = 100 μA; V <sub>CC</sub> = 1.2 V	-	0	-	-	-	V
		I <sub>O</sub> = 100 μA; V <sub>CC</sub> = 2.0 V	-	0	0.2	-	0.2	V
		I <sub>O</sub> = 100 μA; V <sub>CC</sub> = 2.7 V	-	0	0.2	-	0.2	V
		I <sub>O</sub> = 100 μA; V <sub>CC</sub> = 3.0 V	-	0	0.2	-	0.2	V
		I <sub>O</sub> = 100 μA; V <sub>CC</sub> = 4.5 V	-	0	0.2	-	0.2	V
		I <sub>O</sub> = 6 mA; V <sub>CC</sub> = 3.0 V	-	0.25	0.40	-	0.50	V
		I <sub>O</sub> = 12 mA; V <sub>CC</sub> = 4.5 V	-	0.35	0.55	-	0.65	V
I <sub>I</sub>	input leakage current	V <sub>I</sub> = V <sub>CC</sub> or GND; V <sub>CC</sub> = 5.5 V	-	-	1.0	-	1.0	μA
I <sub>CC</sub>	supply current	V <sub>I</sub> = V <sub>CC</sub> or GND; I <sub>O</sub> = 0 A; V <sub>CC</sub> = 5.5 V	-	-	20	-	80	μA
ΔI <sub>CC</sub>	additional supply current	per input; V <sub>I</sub> = V <sub>CC</sub> - 0.6 V; V <sub>CC</sub> = 2.7 V to 3.6 V	-	-	500	-	850	μA
C <sub>I</sub>	input capacitance		-	3.5	-	-	-	pF

[1] Typical values are measured at T<sub>amb</sub> = 25 °C.

## 10. Dynamic characteristics

**Table 8. Dynamic characteristics**  
*GND = 0 V; For test circuit see [Figure 8](#).*

Symbol	Parameter	Conditions	-40 °C to +85 °C			-40 °C to +125 °C		Unit
			Min	Typ <sup>[1]</sup>	Max	Min	Max	
t <sub>pd</sub>	propagation delay	nCP to nQ, n $\bar{Q}$ ; see <a href="#">Figure 6</a> <sup>[2]</sup>						
		V <sub>CC</sub> = 1.2 V	-	70	-	-	-	ns
		V <sub>CC</sub> = 2.0 V	-	24	44	-	56	ns
		V <sub>CC</sub> = 2.7 V	-	18	28	-	41	ns
		V <sub>CC</sub> = 3.3 V; C <sub>L</sub> = 15 pF	-	11	-	-	-	ns
		V <sub>CC</sub> = 3.0 V to 3.6 V <sup>[3]</sup>	-	13	26	-	33	ns
		V <sub>CC</sub> = 4.5 V to 5.5 V <sup>[3]</sup>	-	9.5	17	-	23	ns
		n $\bar{S}$ D to nQ, n $\bar{Q}$ ; n $\bar{R}$ D to nQ, n $\bar{Q}$ ; see <a href="#">Figure 7</a>						
		V <sub>CC</sub> = 1.2 V	-	90	-	-	-	ns
		V <sub>CC</sub> = 2.0 V	-	31	46	-	58	ns
		V <sub>CC</sub> = 2.7 V	-	23	34	-	43	ns
		V <sub>CC</sub> = 3.3 V; C <sub>L</sub> = 15 pF	-	14	-	-	-	ns
		V <sub>CC</sub> = 3.0 V to 3.6 V <sup>[3]</sup>	-	17	27	-	34	ns
		V <sub>CC</sub> = 4.5 V to 5.5 V <sup>[3]</sup>	-	12	19	-	24	ns
t <sub>w</sub>	pulse width	clock HIGH or LOW; see <a href="#">Figure 6</a> ; set or reset LOW; see <a href="#">Figure 7</a>						
		V <sub>CC</sub> = 2.0 V	34	10	-	41	-	ns
		V <sub>CC</sub> = 2.7 V	25	8	-	30	-	ns
		V <sub>CC</sub> = 3.0 V to 3.6 V <sup>[3]</sup>	20	7	-	24	-	ns
		V <sub>CC</sub> = 4.5 V to 5.5 V <sup>[3]</sup>	15	6	-	18	-	ns
t <sub>rec</sub>	recovery time	set or reset; see <a href="#">Figure 7</a>						
		V <sub>CC</sub> = 1.2 V	-	5	-	-	-	ns
		V <sub>CC</sub> = 2.0 V	14	2	-	15	-	ns
		V <sub>CC</sub> = 2.7 V	10	1	-	11	-	ns
		V <sub>CC</sub> = 3.0 V to 3.6 V <sup>[3]</sup>	8	1	-	9	-	ns
		V <sub>CC</sub> = 4.5 V to 5.5 V <sup>[3]</sup>	6	1	-	7	-	ns
t <sub>su</sub>	set-up time	nD to nCP; see <a href="#">Figure 6</a>						
		V <sub>CC</sub> = 1.2 V	-	10	-	-	-	ns
		V <sub>CC</sub> = 2.0 V	22	4	-	26	-	ns
		V <sub>CC</sub> = 2.7 V	12	3	-	15	-	ns
		V <sub>CC</sub> = 3.0 V to 3.6 V <sup>[3]</sup>	8	2	-	10	-	ns
		V <sub>CC</sub> = 4.5 V to 5.5 V <sup>[3]</sup>	6	1	-	8	-	ns

**Table 8. Dynamic characteristics ...continued**  
*GND = 0 V; For test circuit see Figure 8.*

Symbol	Parameter	Conditions	-40 °C to +85 °C			-40 °C to +125 °C		Unit	
			Min	Typ <sup>[1]</sup>	Max	Min	Max		
t <sub>h</sub>	hold time	nD to nCP; see <a href="#">Figure 6</a>							
		V <sub>CC</sub> = 1.2 V	-	-10	-	-	-	ns	
		V <sub>CC</sub> = 2.0 V	3	-2	-	3	-	ns	
		V <sub>CC</sub> = 2.7 V	3	-2	-	3	-	ns	
		V <sub>CC</sub> = 3.0 V to 3.6 V	<a href="#">[3]</a>	3	-2	-	3	-	ns
		V <sub>CC</sub> = 4.5 V to 5.5 V	<a href="#">[3]</a>	3	-2	-	3	-	ns
f <sub>max</sub>	maximum frequency	see <a href="#">Figure 6</a>							
		V <sub>CC</sub> = 2.0 V	14	40	-	12	-	MHz	
		V <sub>CC</sub> = 2.7 V	50	90	-	40	-	MHz	
		V <sub>CC</sub> = 3.3 V; C <sub>L</sub> = 15 pF	-	76	-	-	-	MHz	
		V <sub>CC</sub> = 3.0 V to 3.6 V	<a href="#">[3]</a>	60	100	-	48	-	MHz
		V <sub>CC</sub> = 4.5 V to 5.5 V	<a href="#">[3]</a>	70	110	-	56	-	MHz
C <sub>PD</sub>	power dissipation capacitance	per flip-flop; V <sub>I</sub> = GND to V <sub>CC</sub>	<a href="#">[4]</a>	-	24	-	-	pF	

[1] Typical values are measured at T<sub>amb</sub> = 25 °C.

[2] t<sub>pd</sub> is the same as t<sub>PLH</sub> and t<sub>PHL</sub>.

[3] Typical values are measured at nominal supply voltage (V<sub>CC</sub> = 3.3 V and V<sub>CC</sub> = 5.0 V).

[4] C<sub>PD</sub> is used to determine the dynamic power dissipation (P<sub>D</sub> in μW).

$$P_D = C_{PD} \times V_{CC}^2 \times f_i \times N + \Sigma(C_L \times V_{CC}^2 \times f_o) \text{ where:}$$

f<sub>i</sub> = input frequency in MHz; f<sub>o</sub> = output frequency in MHz

C<sub>L</sub> = output load capacitance in pF

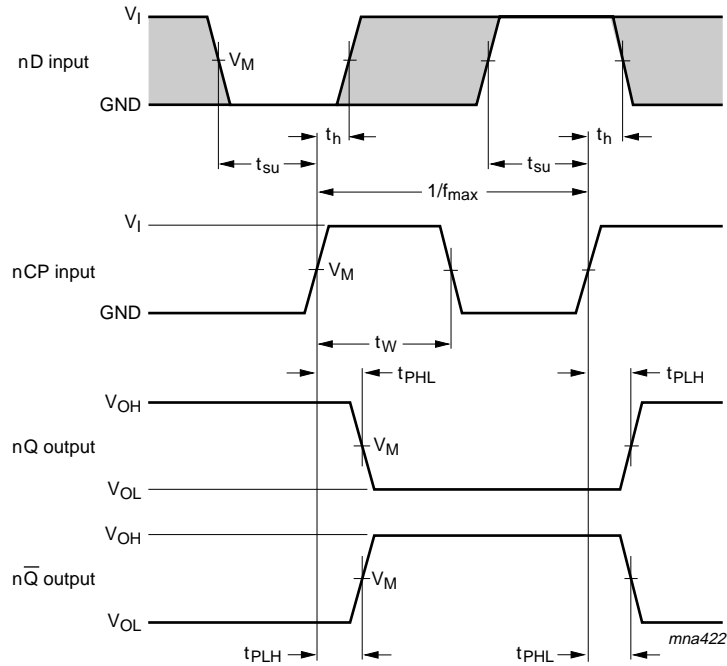
V<sub>CC</sub> = supply voltage in Volts

N = number of inputs switching

Σ(C<sub>L</sub> × V<sub>CC</sub><sup>2</sup> × f<sub>o</sub>) = sum of the outputs



11. Waveforms

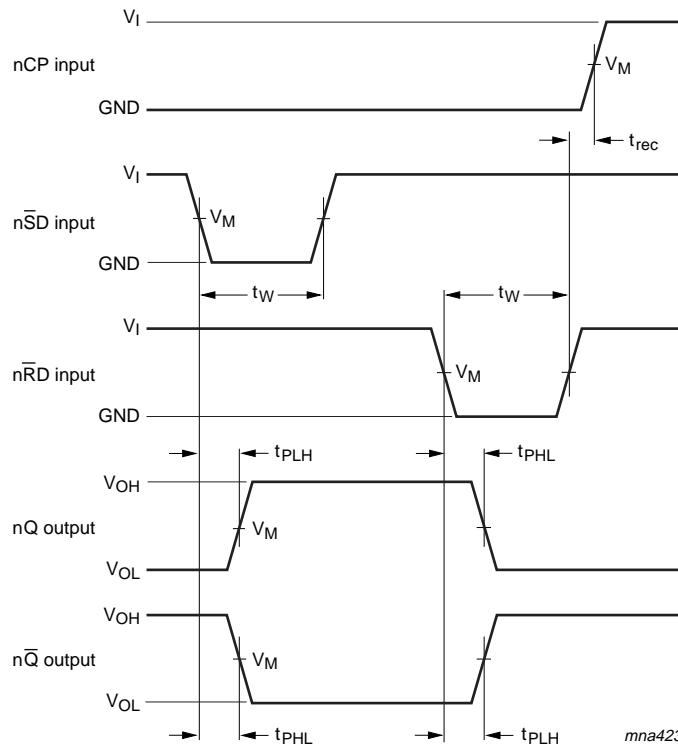


The shaded areas indicate when the input is permitted to change for predictable output performance.

Measurement points are given in [Table 9](#).

$V_{OL}$  and  $V_{OH}$  are typical output voltage drops that occur with the output load.

**Fig 6.** The clock input (nCP) to output (nQ, nQ-bar) propagation delays, the clock pulse width, the nD to nCP set-up, the nCP to nD hold times, and the maximum frequency



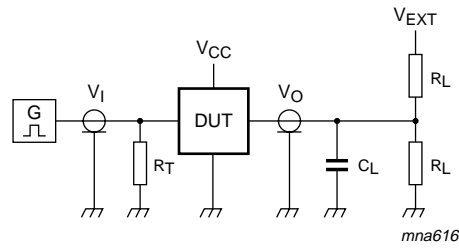
Measurement points are given in [Table 9](#).

$V_{OL}$  and  $V_{OH}$  are typical output voltage drops that occur with the output load.

**Fig 7.** The set ( $n\bar{S}D$ ) and reset ( $n\bar{R}D$ ) input to output ( $nQ$ ,  $n\bar{Q}$ ) propagation delays, the set and reset pulse widths, and the  $n\bar{R}D$  to  $nCP$  recovery time

**Table 9.** Measurement points

Supply voltage	Input	Output
$V_{CC}$	$V_M$	$V_M$
< 2.7 V	$0.5V_{CC}$	$0.5V_{CC}$
2.7 V to 3.6 V	1.5 V	1.5 V
$\geq 4.5$ V	$0.5V_{CC}$	$0.5V_{CC}$



Test data is given in [Table 10](#).

Definitions test circuit:

$R_L$  = Load resistance.

$C_L$  = Load capacitance including jig and probe capacitance.

$R_T$  = Termination resistance should be equal to the output impedance  $Z_o$  of the pulse generator.

$V_{EXT}$  = External voltage for measuring switching times.

**Fig 8. Load circuit for switching times**

**Table 10. Test data**

Supply voltage	Input		Load		$V_{EXT}$		
$V_{CC}$	$V_I$	$t_r, t_f$	$C_L$	$R_L$	$t_{PHL}, t_{PLH}$	$t_{PZH}, t_{PHZ}$	$t_{PZL}, t_{PLZ}$
< 2.7 V	$V_{CC}$	$\leq 2.5$ ns	50 pF	1 k $\Omega$	open	GND	$2V_{CC}$
2.7 V to 3.6 V	2.7 V	$\leq 2.5$ ns	50 pF	1 k $\Omega$	open	GND	$2V_{CC}$
$\geq 4.5$ V	$V_{CC}$	$\leq 2.5$ ns	50 pF	1 k $\Omega$	open	GND	$2V_{CC}$

12. Package outline

DIP14: plastic dual in-line package; 14 leads (300 mil)

SOT27-1

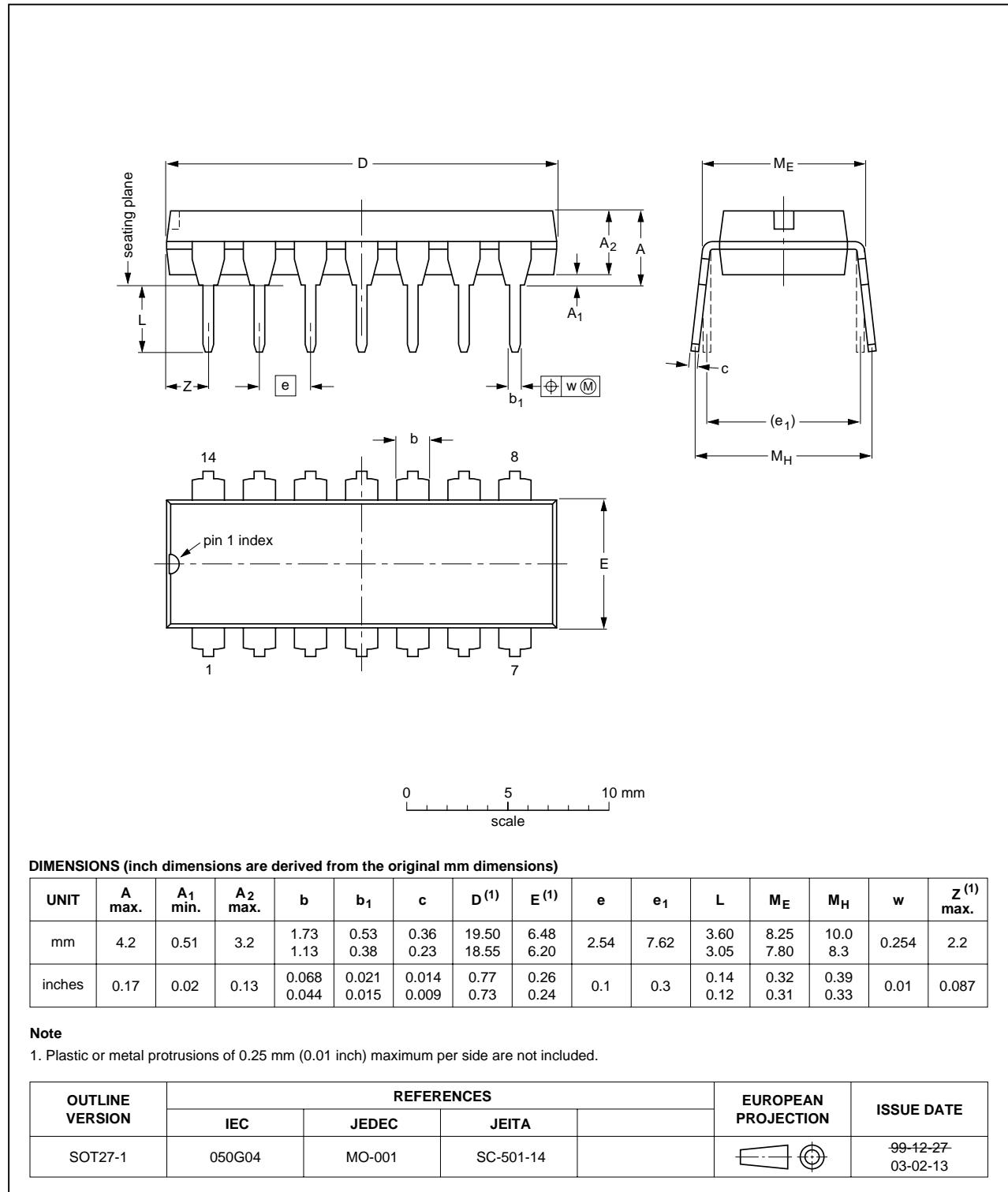


Fig 9. Package outline SOT27-1 (DIP14)

SO14: plastic small outline package; 14 leads; body width 3.9 mm

SOT108-1

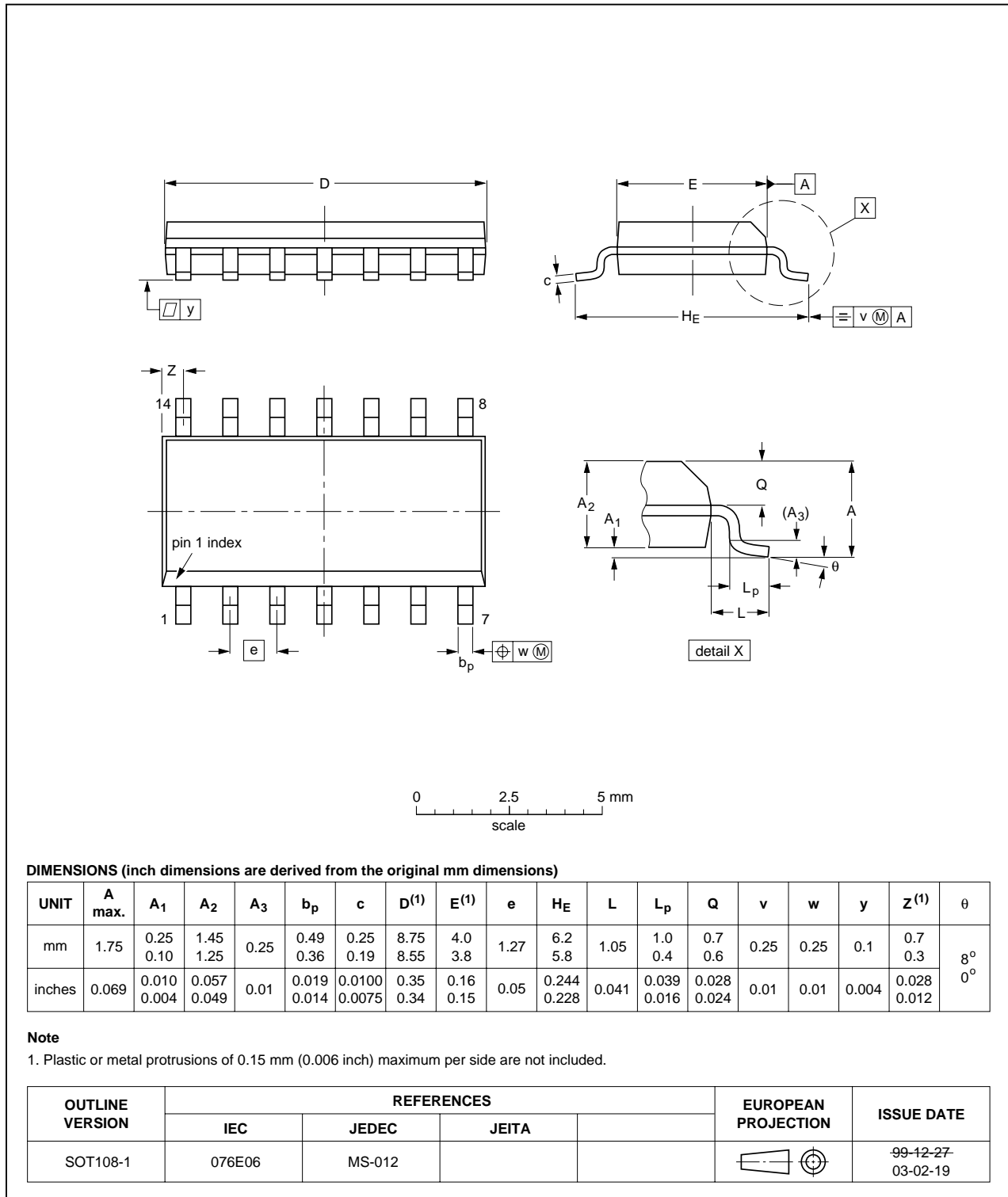


Fig 10. Package outline SOT108-1 (SO14)

SSOP14: plastic shrink small outline package; 14 leads; body width 5.3 mm

SOT337-1

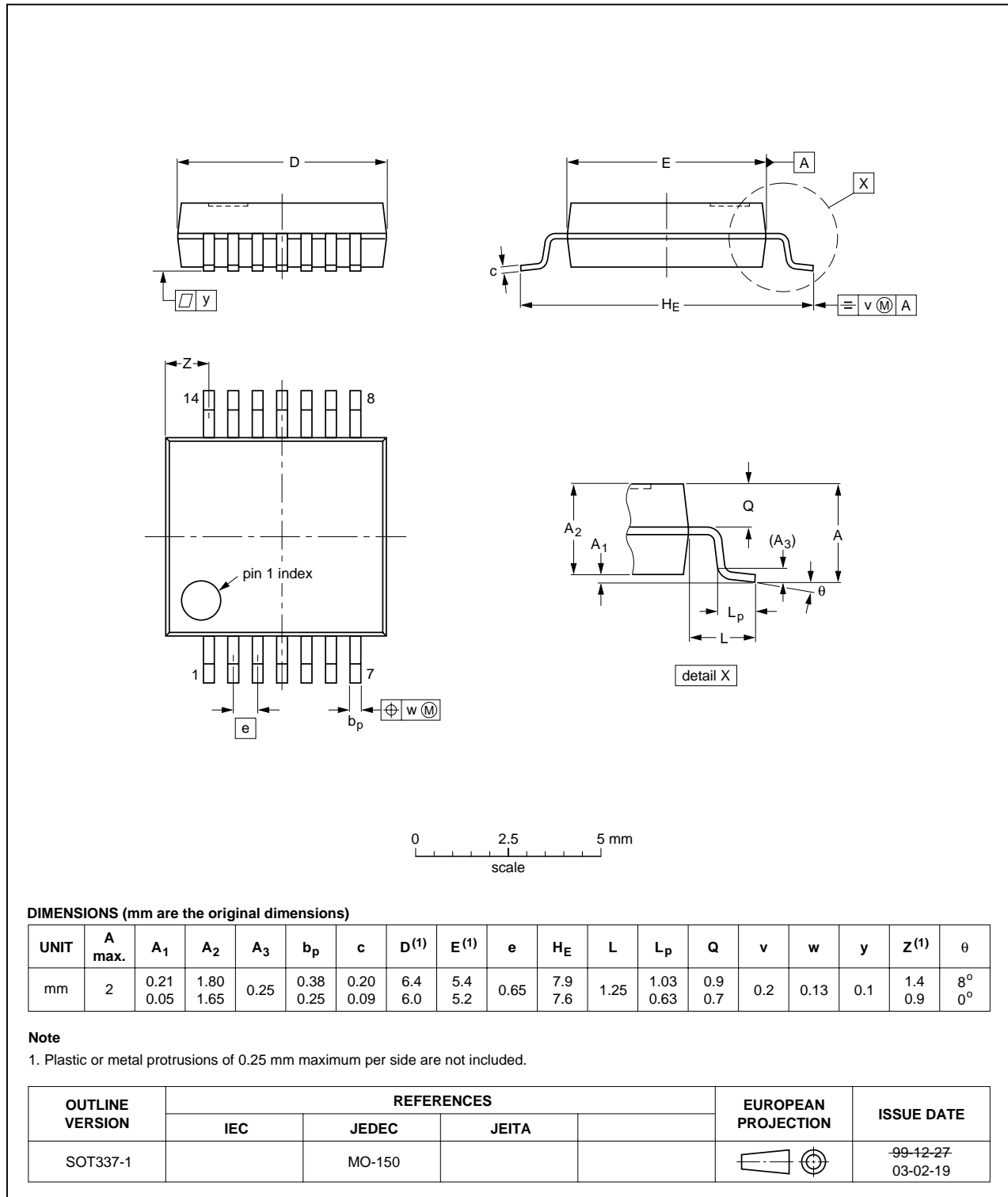


Fig 11. Package outline SOT337-1 (SSOP14)

TSSOP14: plastic thin shrink small outline package; 14 leads; body width 4.4 mm

SOT402-1

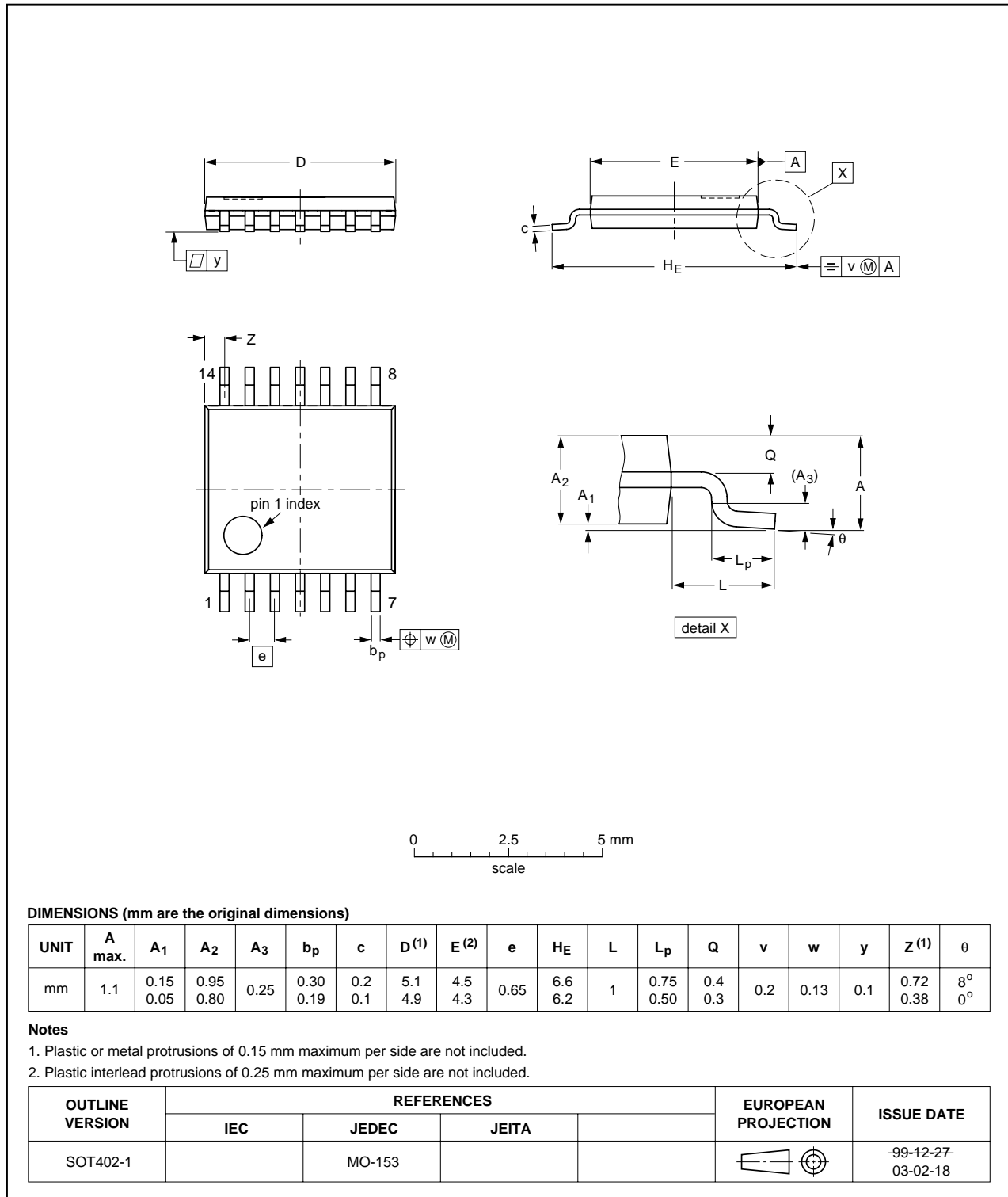


Fig 12. Package outline SOT402-1 (TSSOP14)

DHVQFN14: plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads; 14 terminals; body 2.5 x 3 x 0.85 mm

SOT762-1

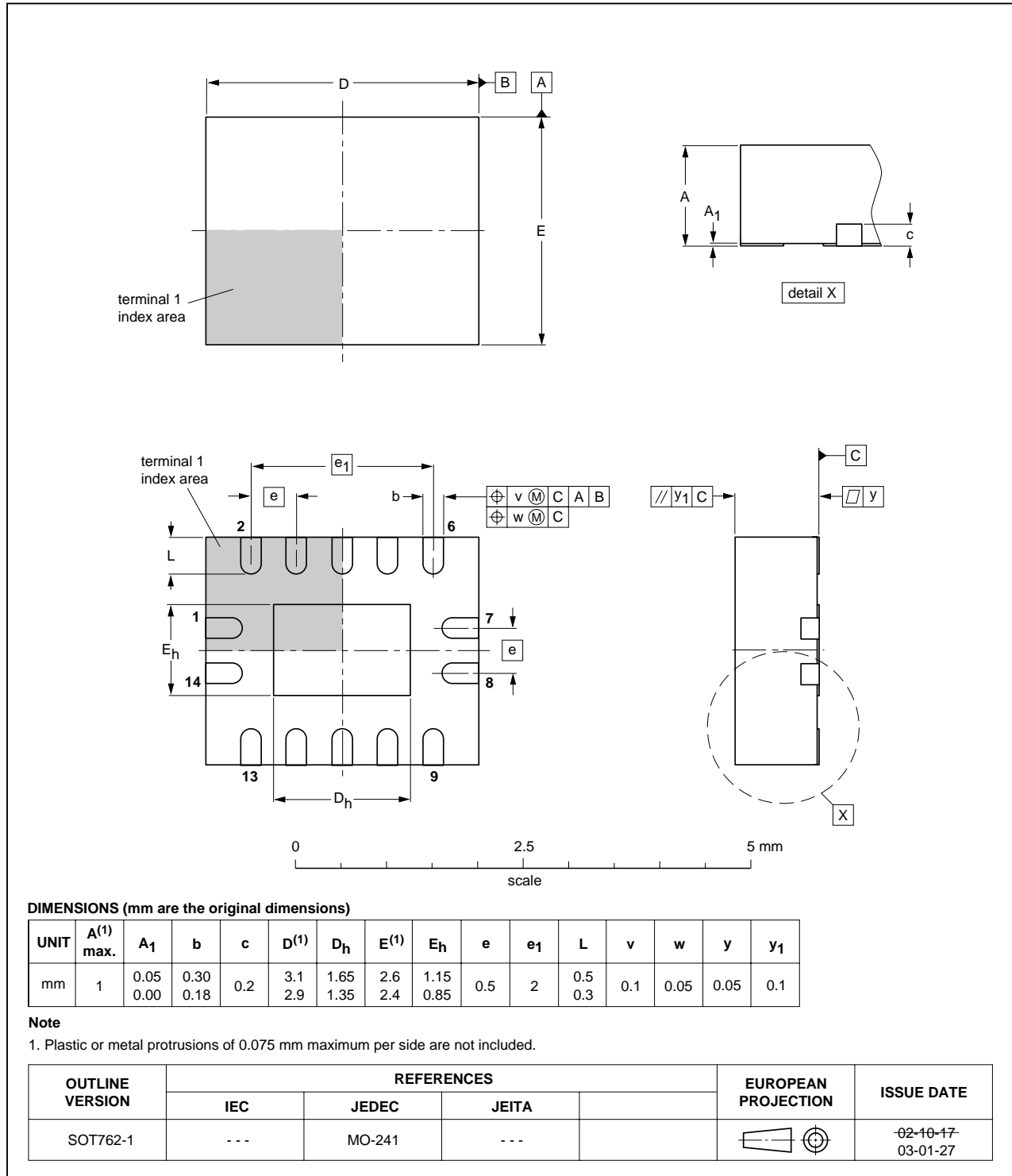


Fig 13. Package outline SOT762-1 (DHVQFN14)



## 13. Abbreviations

Table 11. Abbreviations

Acronym	Description
CMOS	Complementary Metal Oxide Semiconductor
ESD	ElectroStatic Discharge
HBM	Human Body Model
MM	Machine Model
TTL	Transistor-Transistor Logic

## 14. Revision history

Table 12. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
74LV74_3	20070928	Product data sheet	-	74LV74_2
Modifications:	<ul style="list-style-type: none"> <li>• The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors.</li> <li>• Legal texts have been adapted to the new company name when appropriate.</li> <li>• <a href="#">Section 3</a>: DHVQFN14 package added.</li> <li>• <a href="#">Section 7</a>: derating values added for DHVQFN14 package.</li> <li>• <a href="#">Section 12</a>: outline drawing added for DHVQFN14 package.</li> </ul>			
74LV74_2	19980420	Product specification	-	74LV74_1
74LV74_1	19961107	Product specification	-	-

## 15. Legal information

### 15.1 Data sheet status

Document status <sup>[1][2]</sup>	Product status <sup>[3]</sup>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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